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conductor in the co-planar conductor structure being formed to be individually free in space and resilient in relation to the dielectric, a respective gap being formed between each pair of conductors in the co-planar conductor structure from the co-axial cable end to the contact end in such a way that a constant characteristic impedance is obtained from the co-axial cable end to the contact end.

2. (amended) Measuring probe according to claim 1, wherein the respective gap is wider in the region of the dielectric than in the region of the co-planar conductor structure where there is no dielectric.

3. (amended) Measuring probe according to claim 1, wherein the dielectric includes at least one block of quartz.

4. (amended) Measuring probe according to claim 1, wherein the dielectric has, on a side where it is connected to the co-planar conductor structure, a metal coating having substantially the same shape as the co-planar conductor structure.

5. (amended) Measuring probe according to claim 1, wherein the dielectric is metallised over its full area on a side remote from the co-planar conductor structure.

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6. (amended) Measuring probe according to claim 1, further including a planar circuit arranged at the co-axial cable end.

Please add new claims 7 and 8 as follows:

--7. (new) The measuring probe of claim 6 wherein the planar circuit includes at least one active circuit element.

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--8. (new) The measuring probe of claim 1 wherein the dielectric is on both sides of the co-planar conductor structure.--